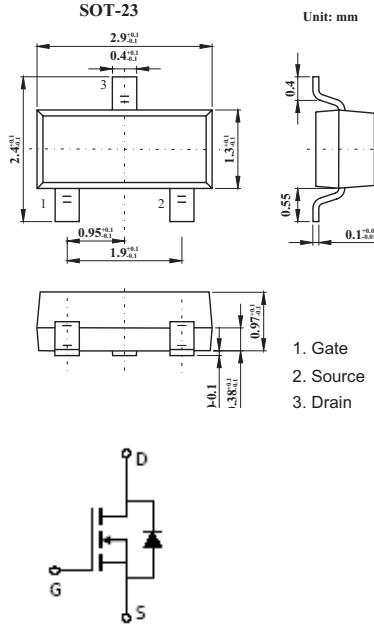


N-Channel Enhancement Mode Field Effect Transistor
■ Features

- $V_{DS(V)} = 30V$
- $I_D = 5.8 A (V_{GS} = 10V)$
- $R_{DS(ON)} < 28m\Omega (V_{GS} = 10V)$
- $R_{DS(ON)} < 33m\Omega (V_{GS} = 4.5V)$
- $R_{DS(ON)} < 52m\Omega (V_{GS} = 2.5V)$


■ Absolute Maximum Ratings $T_a = 25^\circ C$

Parameter	Symbol	Rating	Unit
Drain-Source Voltage	V_{DS}	30	V
Gate-Source Voltage	V_{GS}	± 12	V
Continuous Drain Current $T_a=25^\circ C$	I_D	5.8	A
$T_a=70^\circ C$		4.9	
Pulsed Drain Current *	I_{DM}	30	
Power Dissipation $T_a=25^\circ C$	P_D	1.4	W
$T_a=70^\circ C$		1	
Thermal Resistance.Junction- to-Ambient	R_{thJA}	85	$^\circ C/W$
Thermal Resistance.Junction- to-Case	R_{thc}	43	$^\circ C/W$
Junction and Storage Temperature Range	T_J, T_{STG}	-55 to 150	$^\circ C$

* Repetitive rating, pulse width limited by junction temperature.

■ Electrical Characteristics Ta = 25°C

Parameter	Symbol	Testconditons	Min	Typ	Max	Unit
Drain-Source Breakdown Voltage	V _{DSS}	I _D =250 μ A, V _{GS} =0V	30			V
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} =24V, V _{GS} =0V			1	μ A
		V _{DS} =24V, V _{GS} =0V, T _J =55°C			5	
Gate-Body leakage current	I _{GSS}	V _{DS} =0V, V _{GS} =±12V			±100	nA
Gate Threshold Voltage	V _{GS(th)}	V _{DS} =V _{GS} I _D =250 μ A	0.7	1.1	1.4	V
Static Drain-Source On-Resistance	R _{DSS(ON)}	V _{GS} =10V, I _D =5.8A		22.8	28	mΩ
		V _{GS} =10V, I _D =5.8A T _J =125°C		32	39	
		V _{GS} =4.5V, I _D =5A		27.3	33	
		V _{GS} =2.5V, I _D =4A		43.3	52	
On state drain current	I _{D(ON)}	V _{GS} =4.5V, V _{DS} =5V	30			A
Forward Transconductance	g _{FS}	V _{DS} =5V, I _D =5A	10	15		S
Input Capacitance	C _{iss}	V _{GS} =0V, V _{DS} =15V, f=1MHz		823	1050	pF
Output Capacitance	C _{oss}			99		pF
Reverse Transfer Capacitance	C _{rss}			77		pF
Gate resistance	R _g	V _{GS} =0V, V _{DS} =0V, f=1MHz		1.4	2	Ω
Total Gate Charge	Q _g	V _{GS} =4.5V, V _{DS} =15V, I _D =5.8A		9.7	12	nC
Gate Source Charge	Q _{gs}			1.6		nC
Gate Drain Charge	Q _{gd}			3.1		nC
Turn-On DelayTime	t _{D(on)}	V _{GS} =10V, V _{DS} =15V, R _L =2.7 Ω ,R _{GEN} =3 Ω		3.3	5	ns
Turn-On Rise Time	t _r			4.8	7	ns
Turn-Off DelayTime	t _{D(off)}			26.3	40	ns
Turn-Off Fall Time	t _f			4.1	6	ns
Body Diode Reverse Recovery Time	t _{rr}	I _F =5A, dI/dt=100A/ μ s		16	20	ns
Body Diode Reverse Recovery Charge	Q _{rr}	I _F =5A, dI/dt=100A/ μ s		8.9	12	nC
Maximum Body-Diode Continuous Current	I _s				2.5	A
Pulsed Body-Diode Current *	I _{SM}				30	A
Diode Forward Voltage	V _{SD}	I _s =1A,V _{GS} =0V		0.71	1	V

* Repetitive rating, pulse width limited by junction temperature.

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